

UNISONIC TECHNOLOGIES CO., LTD

F4N60-TC1

Preliminary

Power MOSFET

4.0A, 600V N-CHANNEL POWER MOSFET

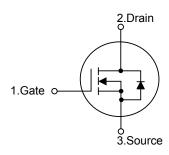
■ DESCRIPTION

The UTC **F4N60-TC1** is a N-Channel enhancement mode silicon gate power MOSFET with Fast Body Diode, is designed high voltage, high speed power switching applications such, is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.



- * $R_{DS(ON)} \le 3.0 \Omega @ V_{GS} = 10V, I_D = 2.0A$
- * Fast body diode MOSFET technology
- * High Switching Speed

■ SYMBOL



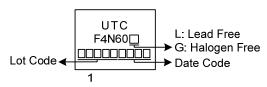
ORDERING INFORMATION

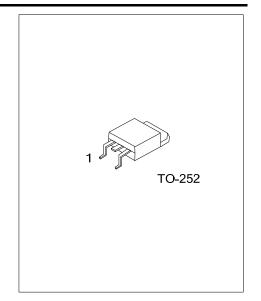
Ordering Number		Dookooo	Pin Assignment			Daakina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
F4N60L-TN3-R	F4N60G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source

F4N60G-TN3-R (1)Packing Type (1) R: Tape Reel (2) TN3: TO-252 (3)Green Package (3) G: Halogen Free and Lead Free, L: Lead Free

MARKING





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■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	600	V	
Gate-Source Voltage		V_{GSS}	± 30	V	
Drain Current	Continuous	I_D	4	Α	
	Pulsed (Note 2)	I_{DM}	8	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	102	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	5.3	V/ns	
Power Dissipation		P_D	50	W	
Junction Temperature		T_J	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 10mH, I_{AS} = 4.5A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 4.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θ_{JA}	θ _{JA} 110		
Junction to Case	θ_{JC}	2.5 (Note)	°C/W	

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS (T_J = 25°C, unless otherwise specified)

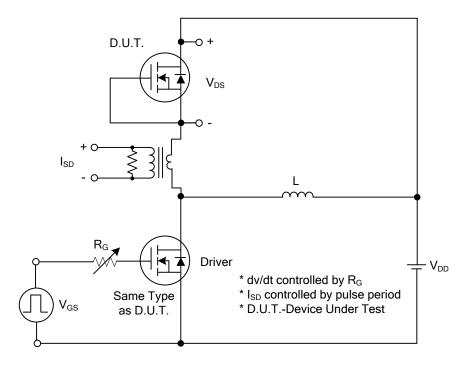
PARAMETER		SYMBOL	TEST CONDITIONS		TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V _{GS} =0V, I _D = 250μA				V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =600V, V _{GS} =0V			10	μΑ
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} =30V, V _{DS} =0V			100	nA
	Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V _{DS} =V _{GS} , I _D =250μA			4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =2.0A			3.0	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}			575.3		pF
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0 MHz		57.9		pF
Reverse Transfer Capacitance		C _{RSS}			3.8		pF
SWITCHING CHARACTERISTICS	3						
Total Gate Charge (Note 1)		Q_{G}	\/ -480\/ \/ -10\/ -40		16.3		nC
Gate-Source Charge		Q_{GS}	V _{DS} =480V, V _{GS} =10V, I _D =4A I _G =1mA (Note 1, 2)		5.8		nC
Gate-Drain Charge		Q_GD	IG-IIIA (Note 1, 2)		2.5		nC
Turn-on Delay Time (Note 1)		$t_{D(ON)}$			8		ns
Rise Time		t_R	V _{DS} =100V, V _{GS} =10V, I _D =4A,		15.7		ns
Turn-off Delay Time		$t_{D(OFF)}$	R _G =25Ω (Note 1, 2)		37.9		ns
Fall-Time		t _F			25.9		ns
SOURCE- DRAIN DIODE RATING	S AND CH	ARACTERIS [*]	TICS				
Maximum Body-Diode Continuous Current		Is				4	Α
Maximum Body-Diode Pulsed Current		I _{SM}				8	Α
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	V _{GS} =0V, I _S =4.0A			1.4	V
Reverse Recovery Time (Note 1)		t _{rr}	V _{GS} =0V, I _S =4.0A,		93.3		ns
Reverse Recovery Charge		Q_{rr}	dI _F /dt=100A/μs (Note1)		0.37		μC

Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

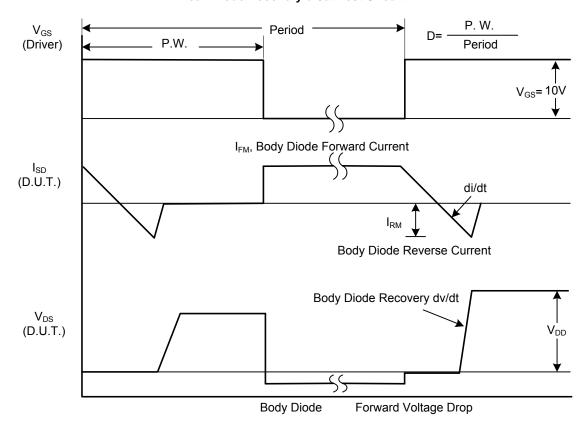
2. Essentially independent of operating temperature.



■ TEST CIRCUITS AND WAVEFORMS

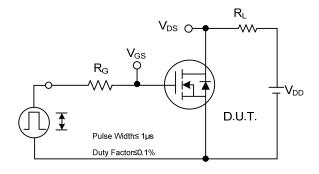


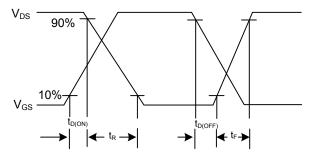
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

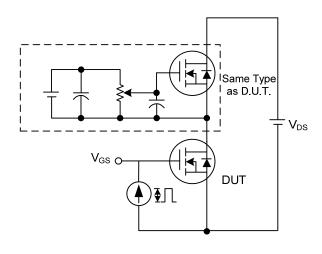
TEST CIRCUITS AND WAVEFORMS

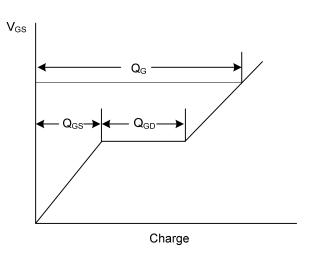




Switching Test Circuit

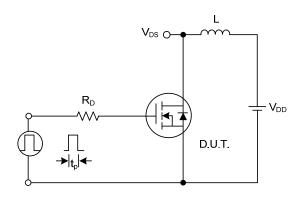
Switching Waveforms

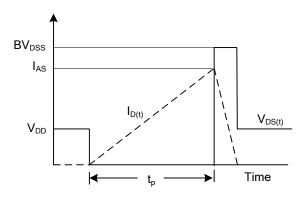




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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